

Research Experiences
For Undergraduates

New tools for understanding Mirror Degradation of Aluminum mirrors with Far Uv and EUV function-

A mirror coating for space with the greatest band width

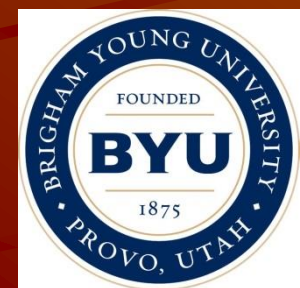
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*Utah NASA Space Human Infrastructure Grant 2015

†NSF- BYU Physics REU/RET contract #PHY1461219
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Undergraduate RA support.



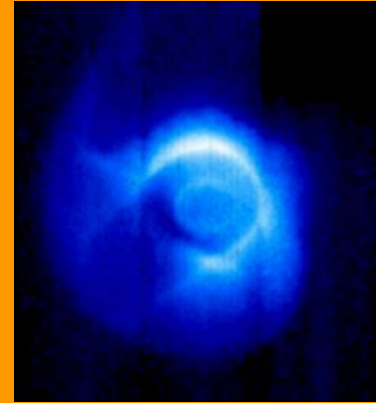
Our group has made spaces mirrors for Far- Extreme Ultraviolet (EUV)

Thin Film U/Si Multilayer Mirrors



EUV Astronomy: IMAGE Mission

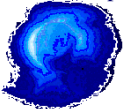
The Earth's magnetosphere is at UHV ($<1\text{E}-8$ torr) but we can see it with the right mirrors.



The Earth's magnetosphere in the EUV-30.4 nm

Tools to study EUV Multilayers

- ❖ Al is partially transparent <70 nm
- ❖ Surfaces- Non Ideal
 - ❖ Roughness, Layers: Oxides, Contamination
- ❖ Optical Constants- $>40\text{nm}$



Summary: What the mirror & coatings might be.

A Multilayer (ML) VUV-EUV Mirror Coated with as Thin as Possible Aluminum Film- without oxide

◆ Processed in Space -

- Processing may mean

- ◆ Al coating* on Earth-prepared EUV-ML mirror.
- ◆ It may mean removal of one or more barrier layers.†
- ◆ Probably both need to be developed.

- Point of use.

- far from Earth.

◆ It is helpful to devise and perfect tools.

* Life prolongation of far ultraviolet reflecting aluminum coatings by periodic recoating of the oxidized surface. Juan Ignacio Larruquert, Jo. Antonio Mendez, Jose Antonio Aznarez, Optics Communications 135 (1997) 60-64 † Burton proposed removing

Our Goals:

- ◆ Doubling* the effective bandwidth for aluminum mirrors .
- ◆ Provide info about tradeoffs to those making decisions for decadal review.
- ◆ Advance the TRL for space-processed bare aluminum mirrors with EUV beneath.
- ◆ Educate students
- ◆ Develop tools

*From current 0 to ~10 eV to 0 to ~20 eV or 0 to 15 + another 5eV further on in EUV
124nm to 62nm or e.g., 124 to 83 & 62-56 nm

OUTLINE

◆ Introduction:

◆ Tool development: How to get bare aluminum in space & study it here:

- Development of two kinds of optical characterization tools

- **Atomic Hydrogen**

- Processing at point of use-

- Removable protective coatings -

Two varieties

1. Preliminary Atomic Hydrogen processing Experiment: Polymer Film removal

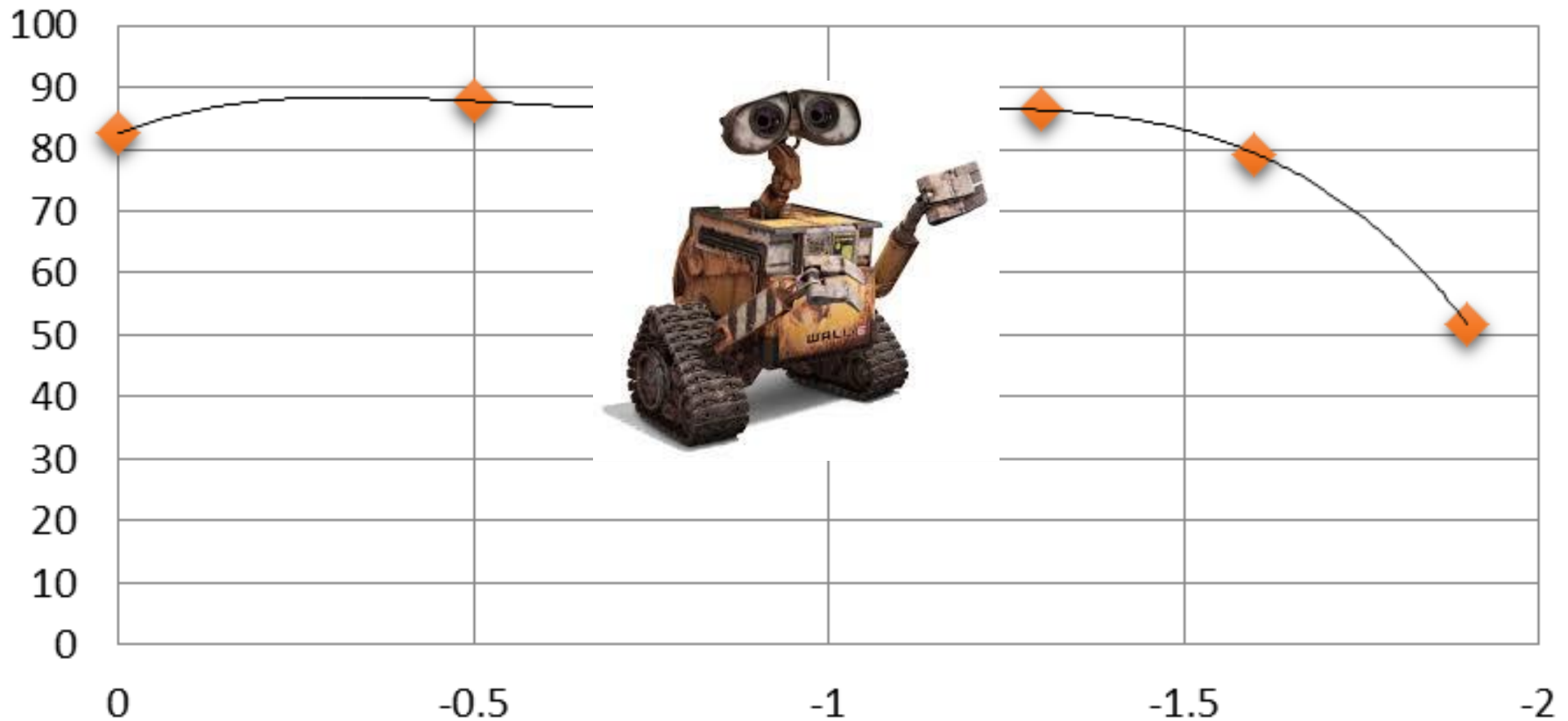
◆ Tasks:

1. Plastic on wafer & fresh PMMA wafers
2. Use a sputter system to plasma etch samples in 100% H₂

$\text{CH}_x\text{O}_y + \text{H} \rightarrow \text{Volatile compounds like Hydrocarbons \& H}_2\text{O}$

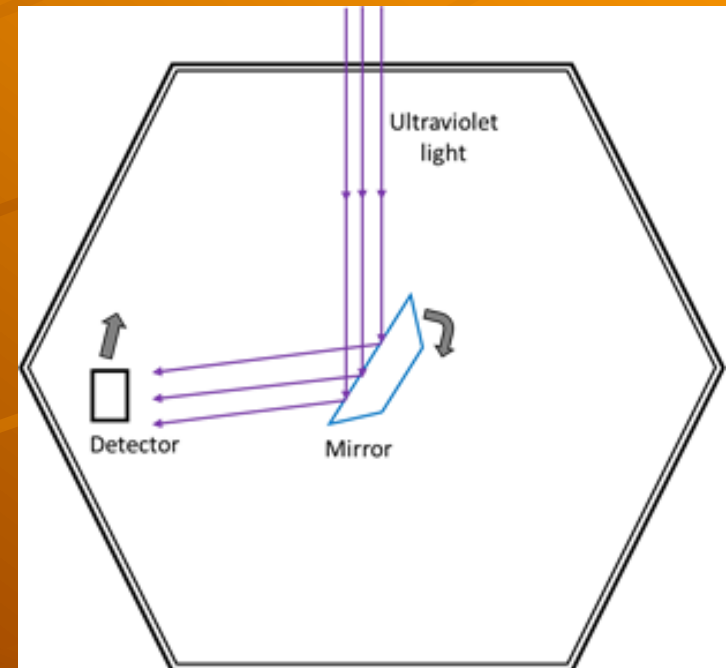
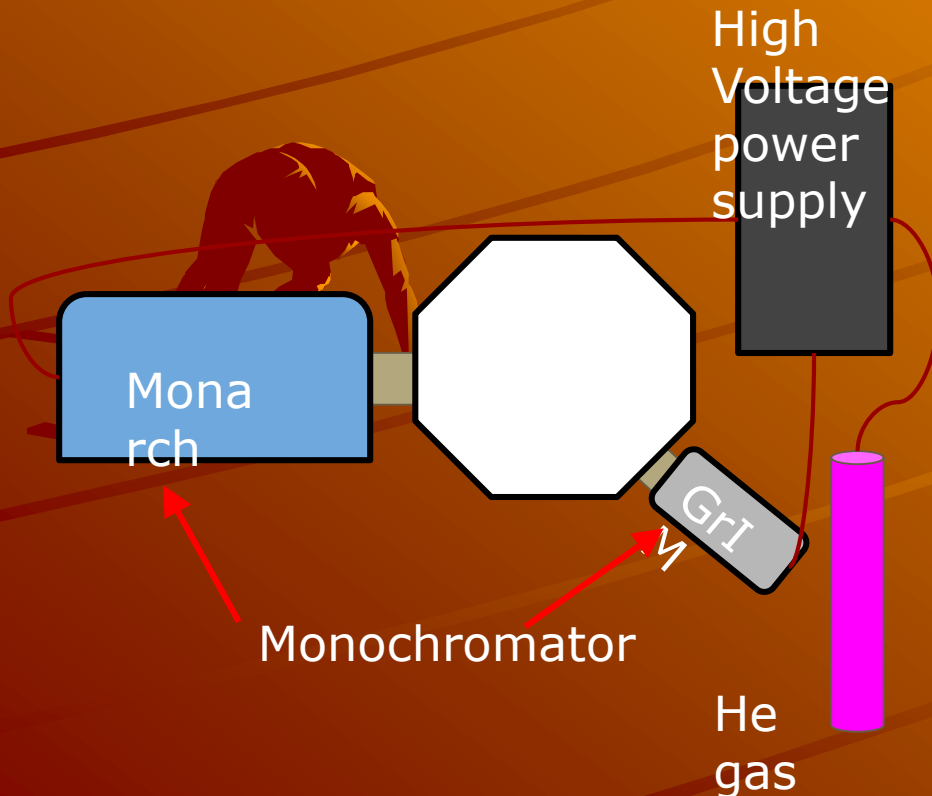


nanometers etched in 8 min. H₂ plasma- from wafer center (0) outward to edge (-2 inches)



2. VUV measurement of Al mirror made in Situ

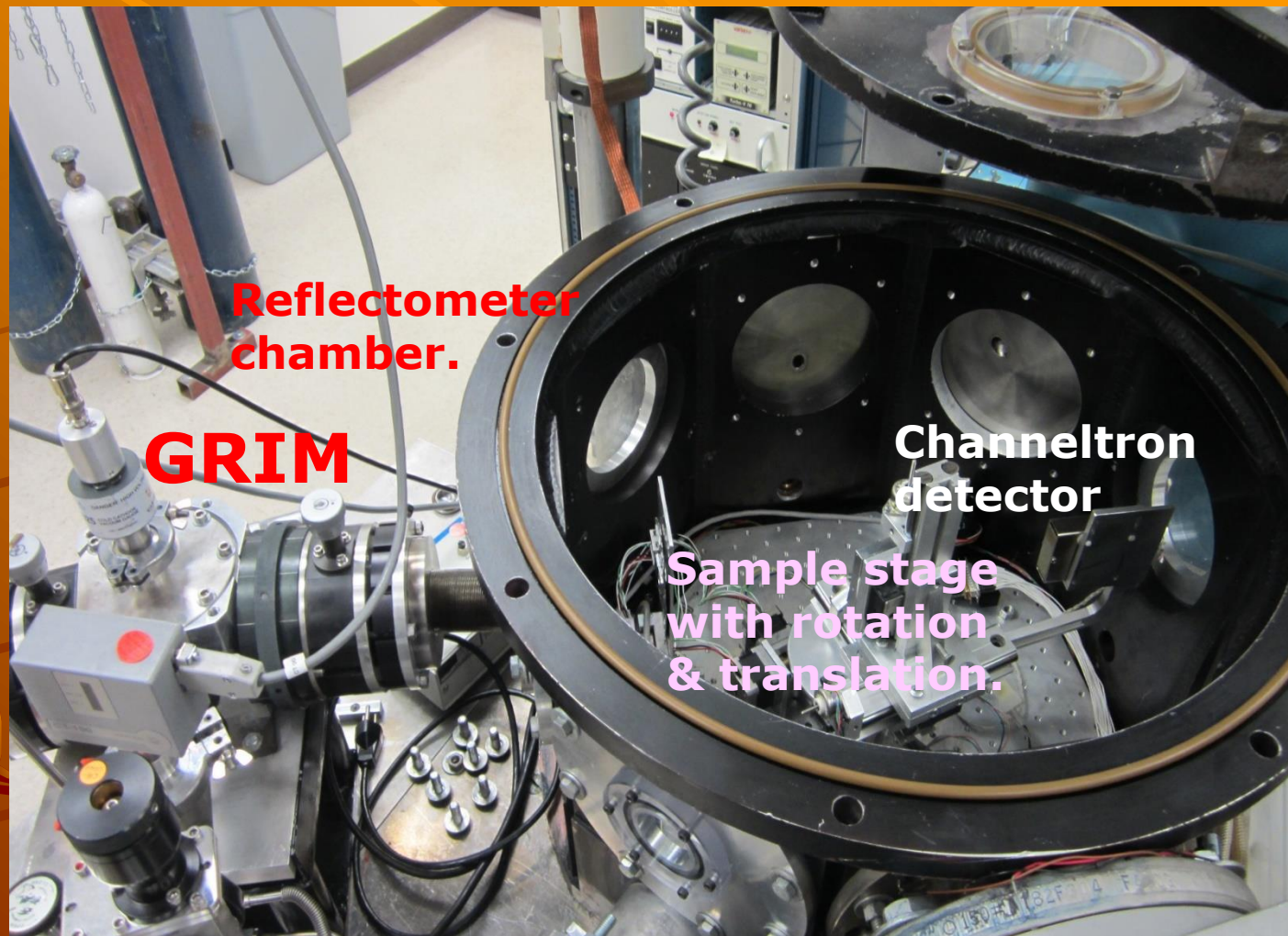
- ◆ An evaporator is being set up to coat the mirror in the chamber itself
- ◆ the mirror will rotate around to where it's used.
- ◆ The evaporator will be pulled back up out of the way so the rotation measurements can be made.



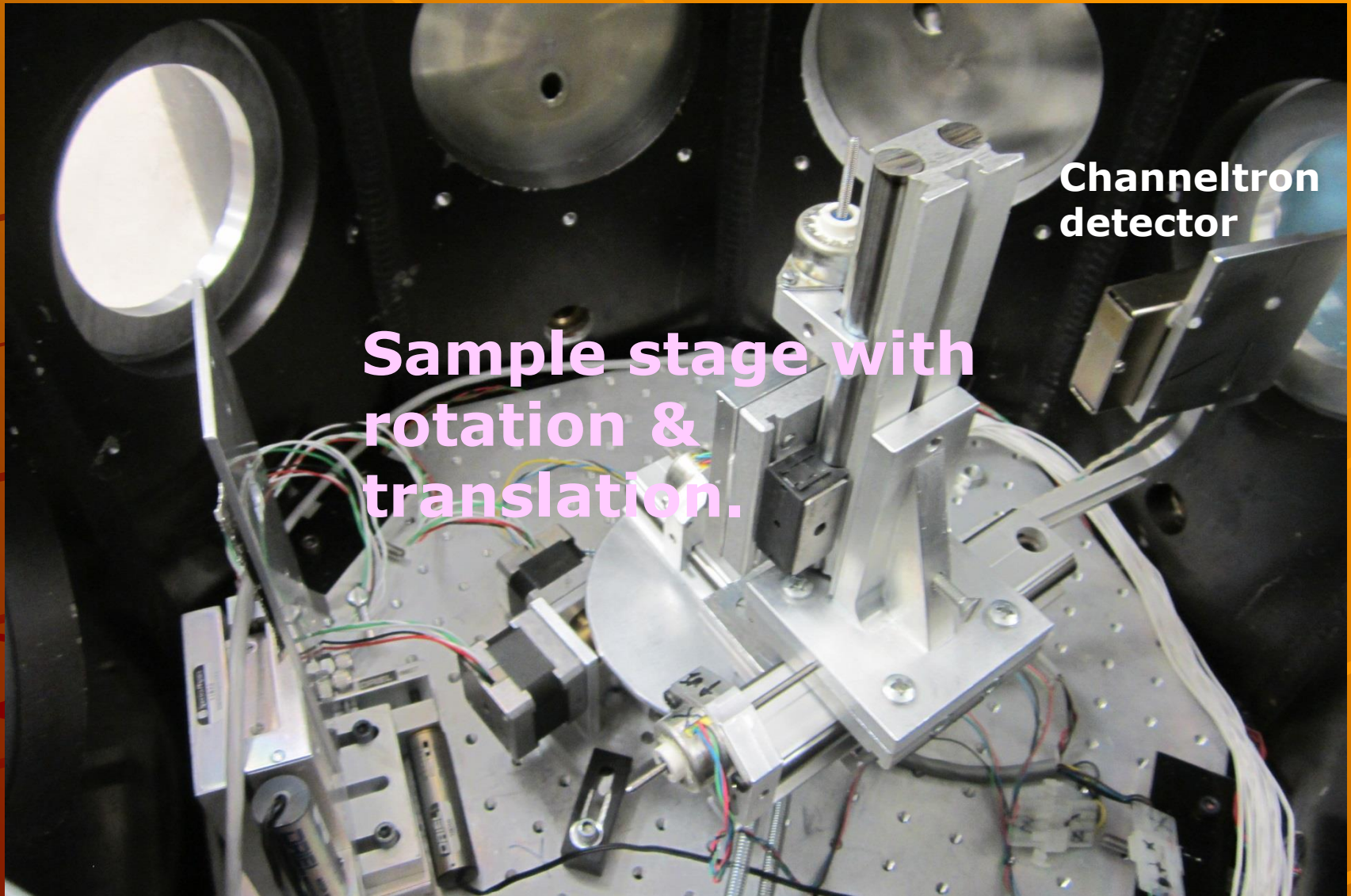
VUV measurement of Al mirror made in Situ

The team:
R Steven
Turley with
Margaret Miles
and
Alexandra
V. Davis.

One of 2 VUV
monochromators
bring UV light



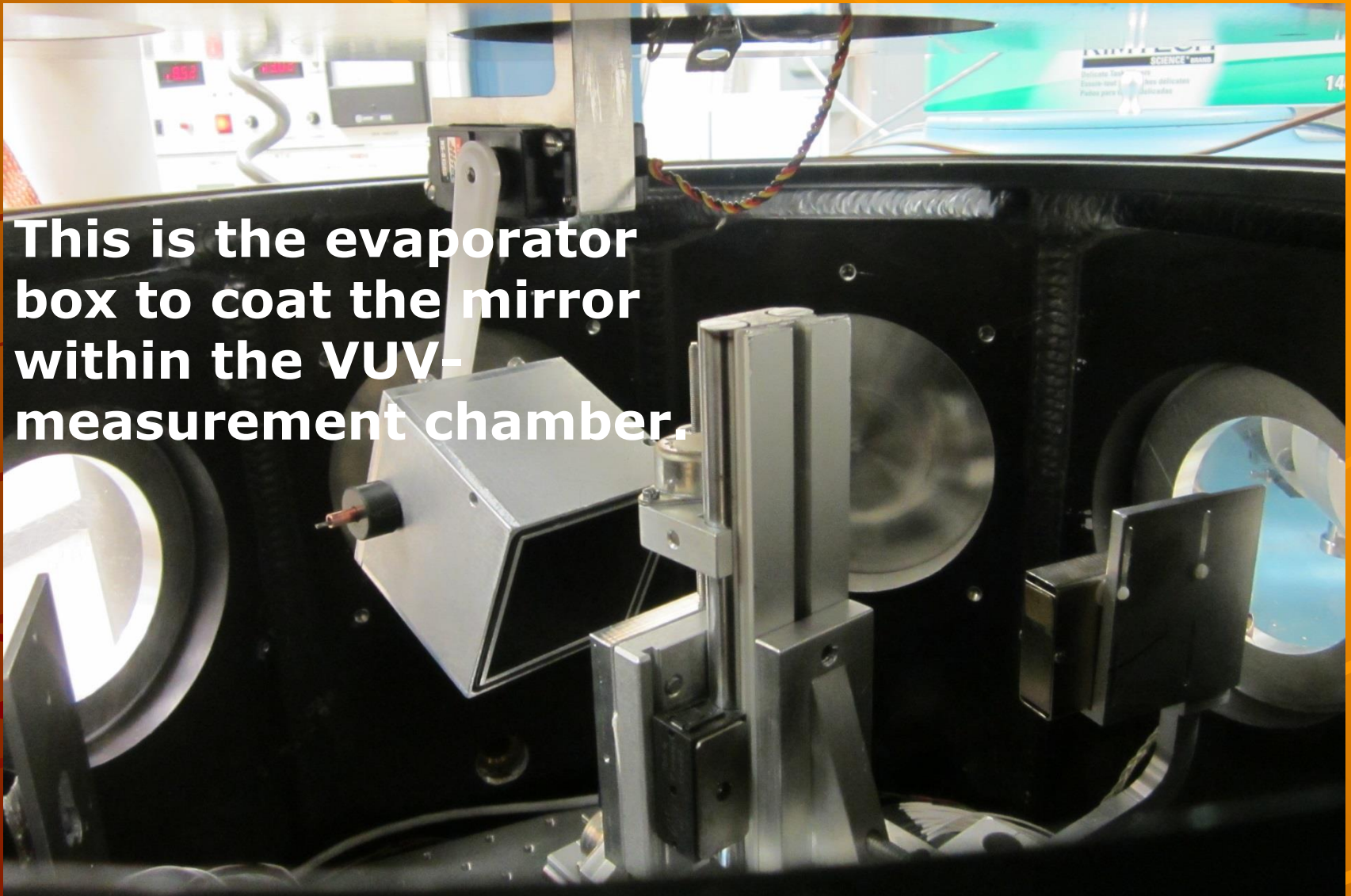
VUV measurement of Al mirror made in Situ



VUV measurement of Al mirror made in Situ

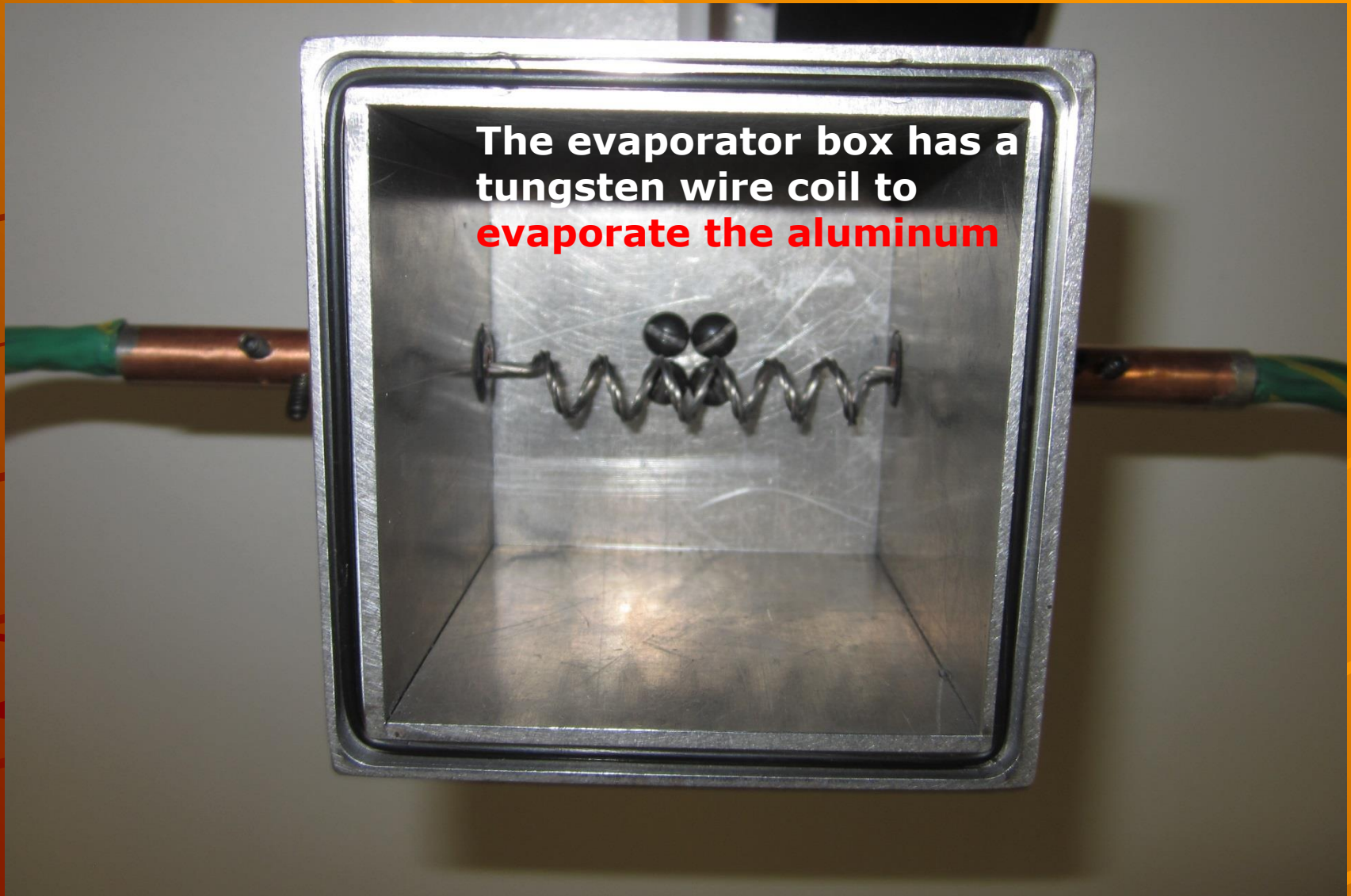
- ◆ Margaret Miles, R Steven Turley
- ◆ VUV monochromators bring light to scattering chamber.
- ◆ An evaporator is being set up to coat the mirror in the VUV-measurement chamber.
- ◆ The mirror will rotate around to where it's used.
- ◆ The evaporator will be pulled back up out of the way so the rotation measurements can be made.

VUV measurement of Al mirror made in Situ



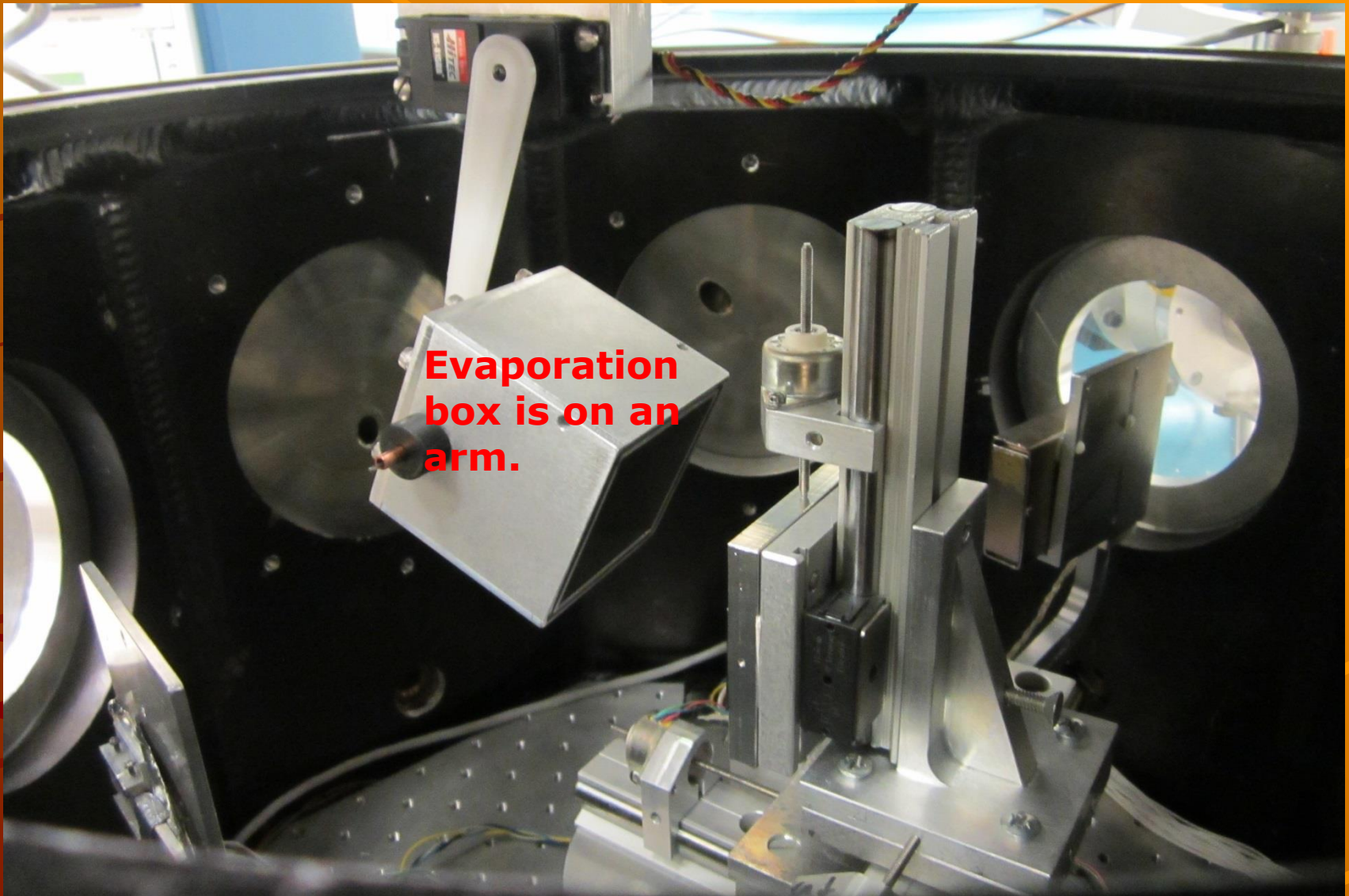
This is the evaporator box to coat the mirror within the VUV-measurement chamber.

VUV measurement of Al mirror made in Situ



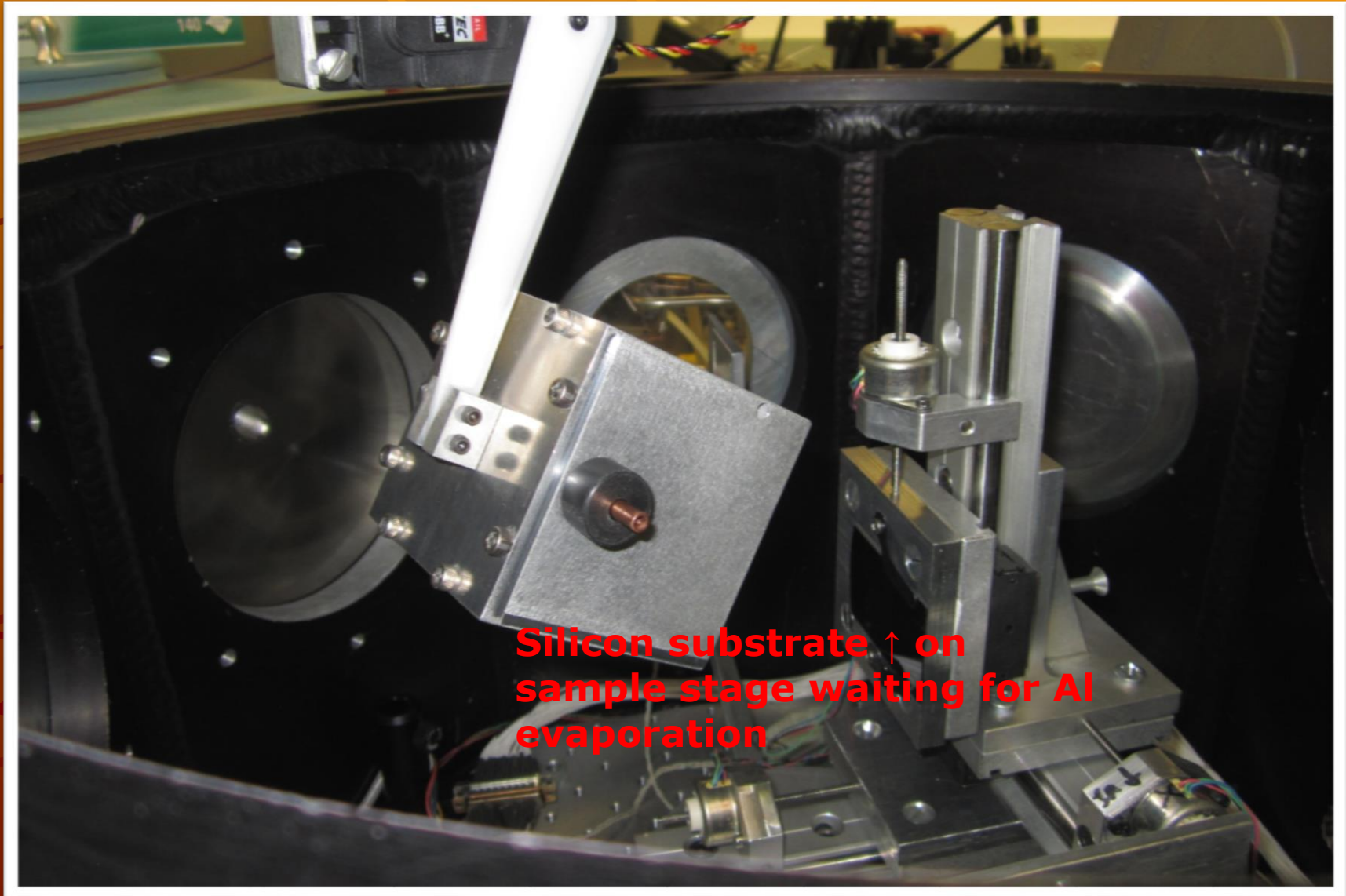
The evaporator box has a tungsten wire coil to **evaporate the aluminum**

VUV measurement of Al mirror made in Situ



**Evaporation
box is on an
arm.**

VUV measurement of Al mirror made in Situ



**Silicon substrate ↑ on
sample stage waiting for Al
evaporation**

VUV measurement of Al mirror made in Situ



VUV measurement of Al mirror made in Situ

◆ Results are still coming.



3. Developing ex situ Tools to see if (& how fast) a surface is oxidizing

◆ **Ellipsometry** and xps (x-ray photoelectron spectroscopy)

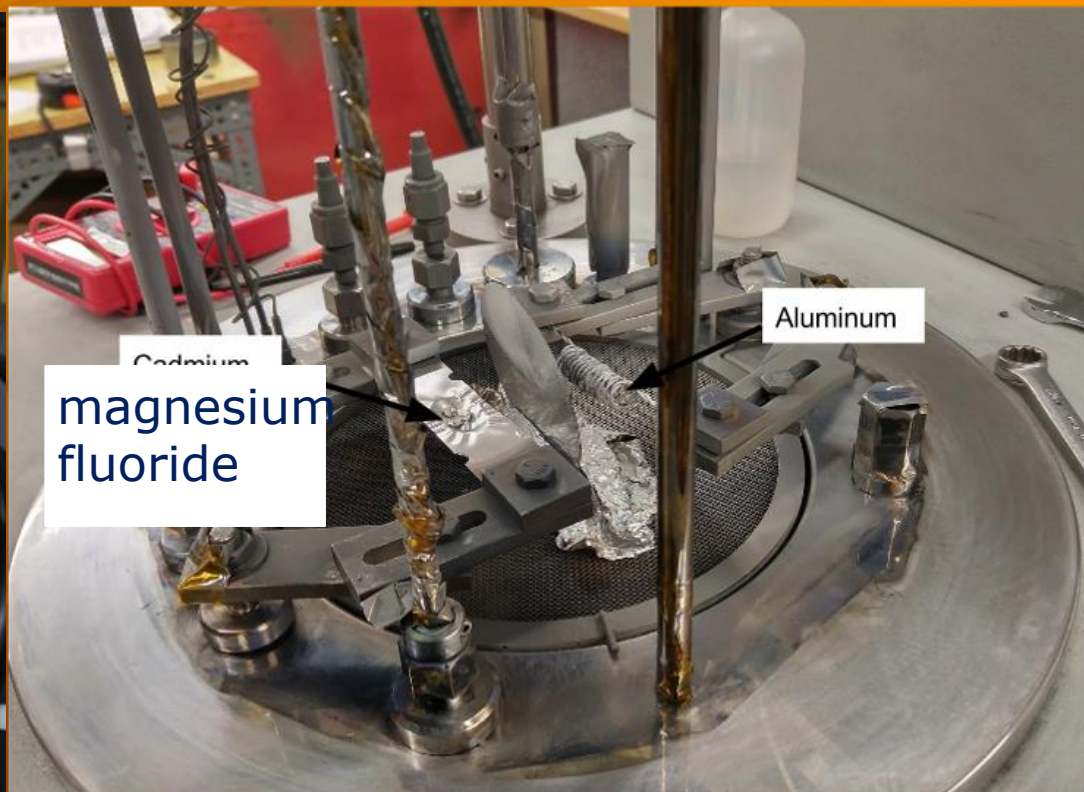


Tool development-

Studying barriers that may or may not be removed.

Watching Al oxidize ex situ under a barrier layer via multiangle, spectroscopic ellipsometry. Michael J. Greenberg

- ✦ We evaporated aluminum and then immediately after magnesium fluoride



Facts about this evaporation:



- **Purpose: see if we can find a simple technique to quantify oxidation**

- **Wasn't meant to provide the best aluminum.**

- Al dep. not fast.
- Starting pressure $4-6 \times 10^{-6}$ torr.

- Purpose: limit oxygen level on Al under MgF_2



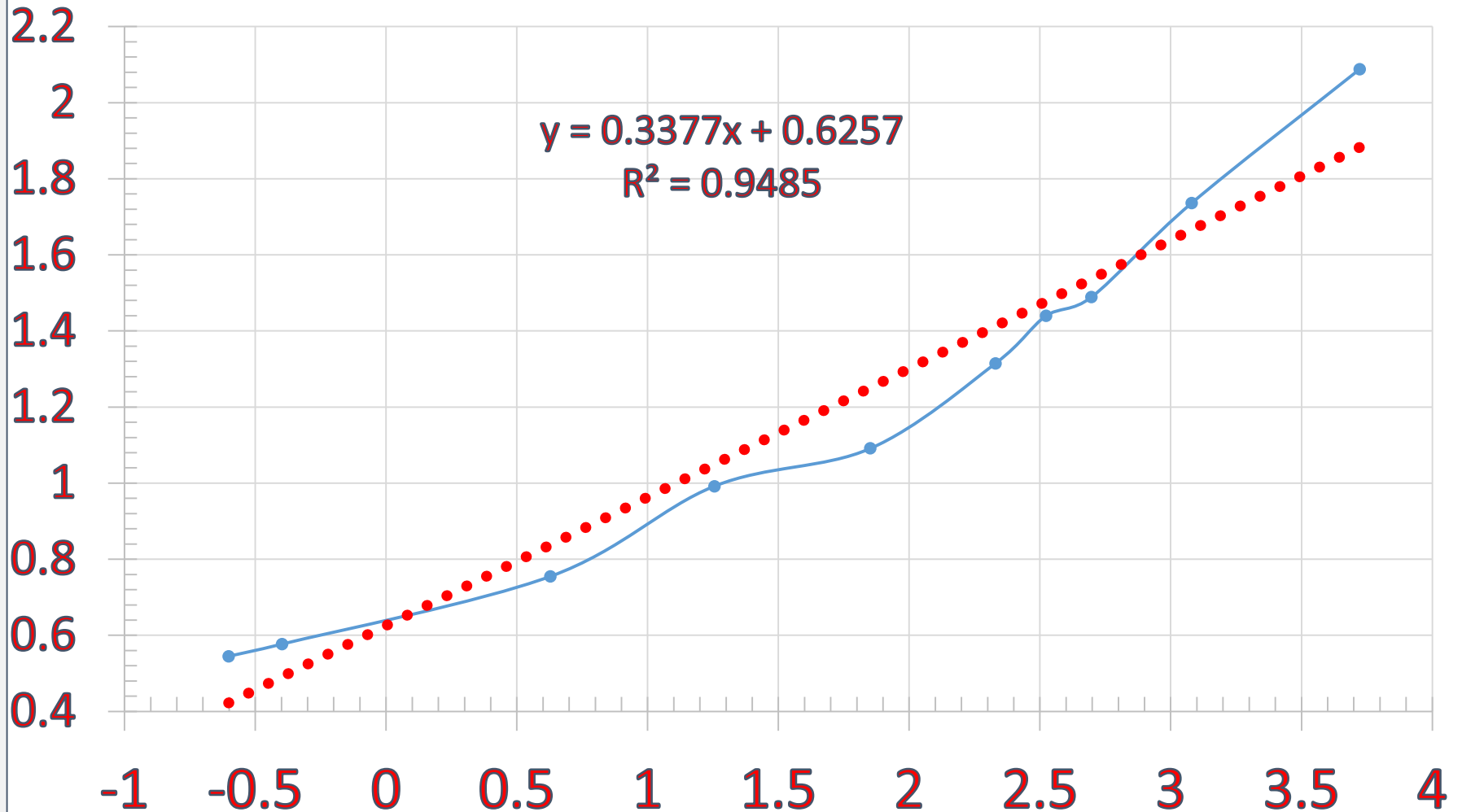
CHROME
COATERS
PA307A389 CB-41

Spectroscopic Ellipsometric measurements

> 8 srough	0.000 nm
7 mgf2	7.455 nm
6 (al2o3_cl1) Coupled to #0	0.489 nm
5 al_palik_g	34.385 nm
4 sinonsio3	694.805 nm
3 sio2_jaw	2.000 nm
2 intr_jaw	0.400 nm
1 si_jaw	10000000.000 nm

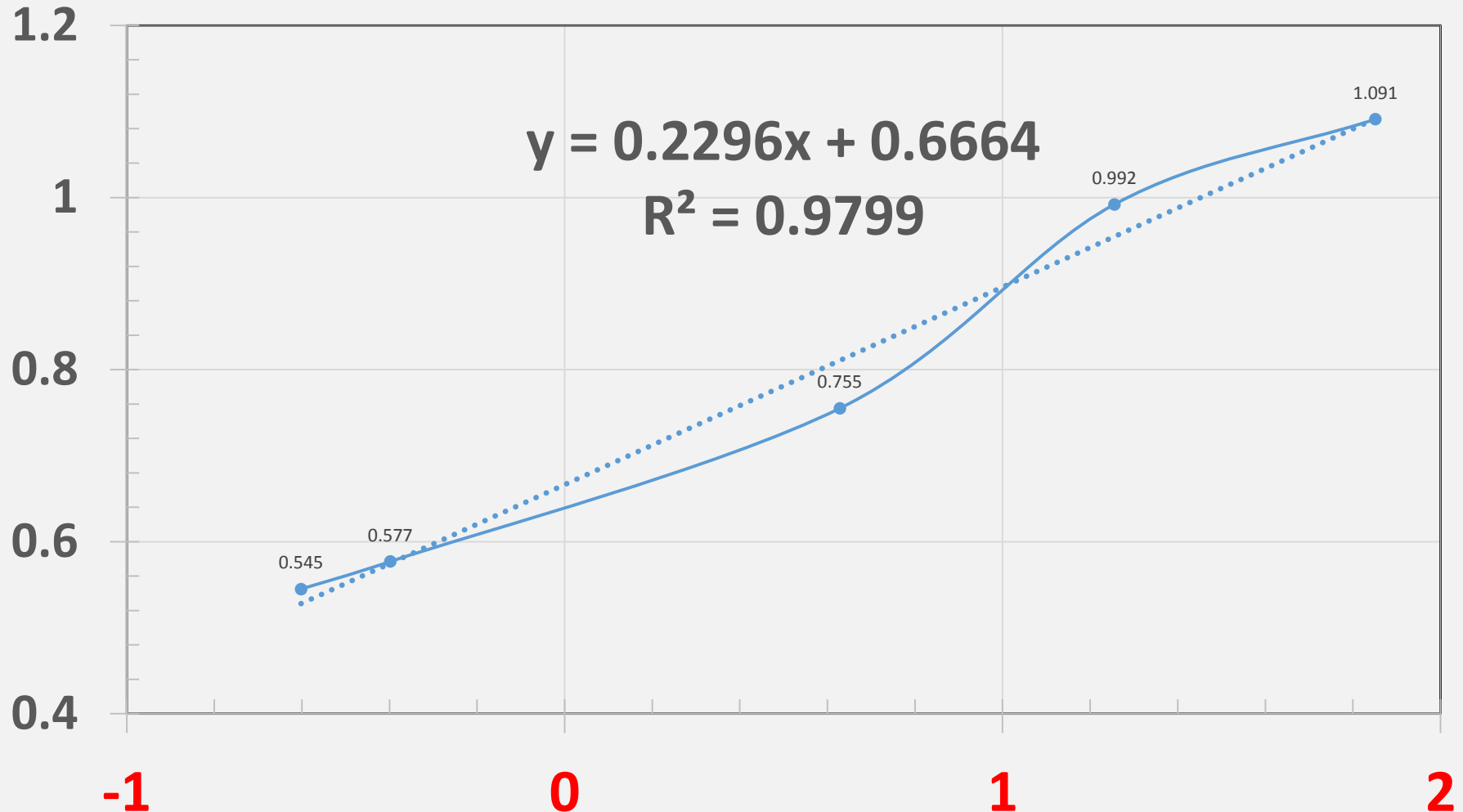
~10,000 values interpreted with small # of numbers: thicknesses & # that describe how index changes with wavelength. (Parametric model)

modelled alumina thickness in nm vs. log[time(hr)]-
Si3N4 thickness also fit



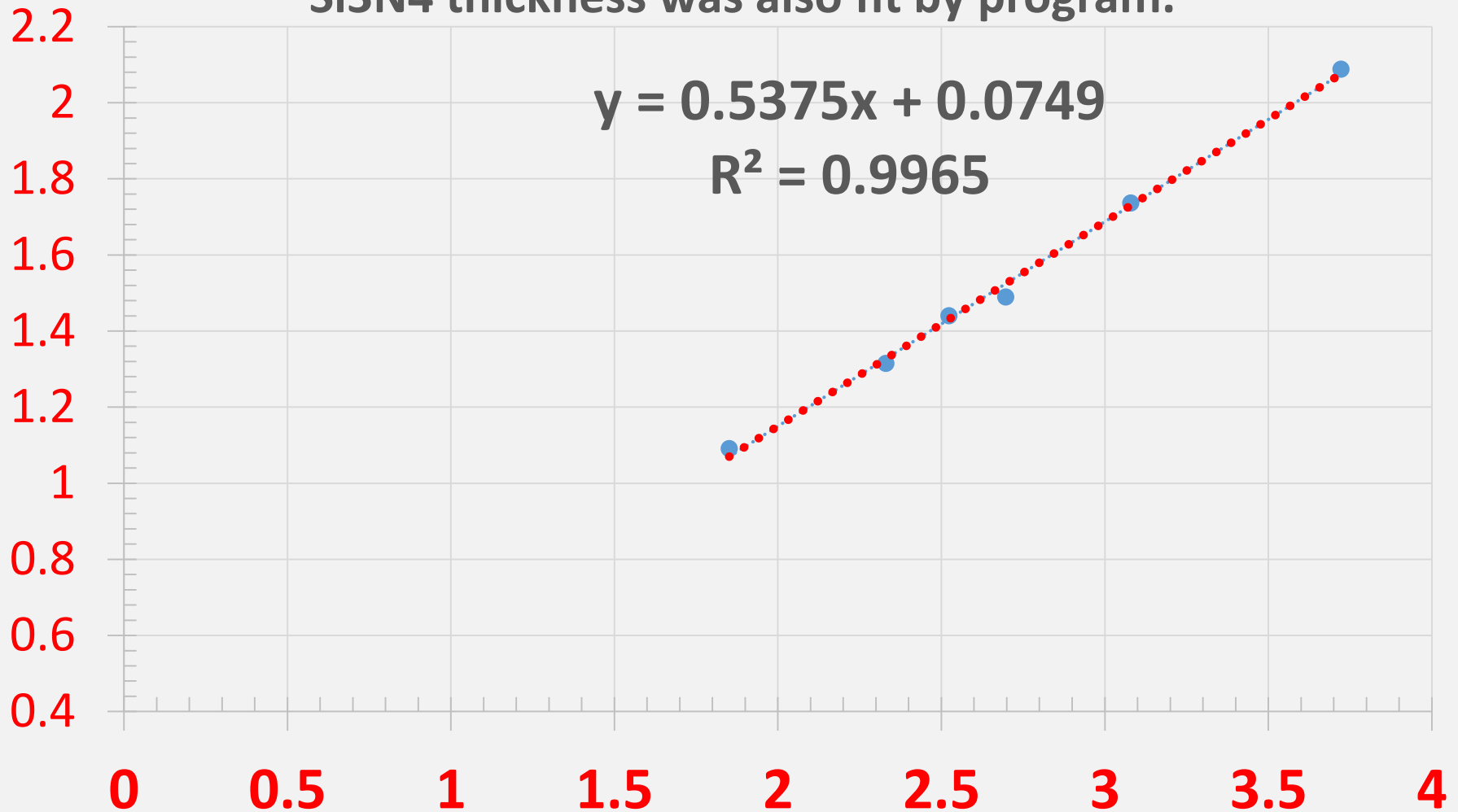
Ellipsometric measurements

Alumina thickness log[time(hr)]-in nm
Si₃N₄ thickness was also fit by program.



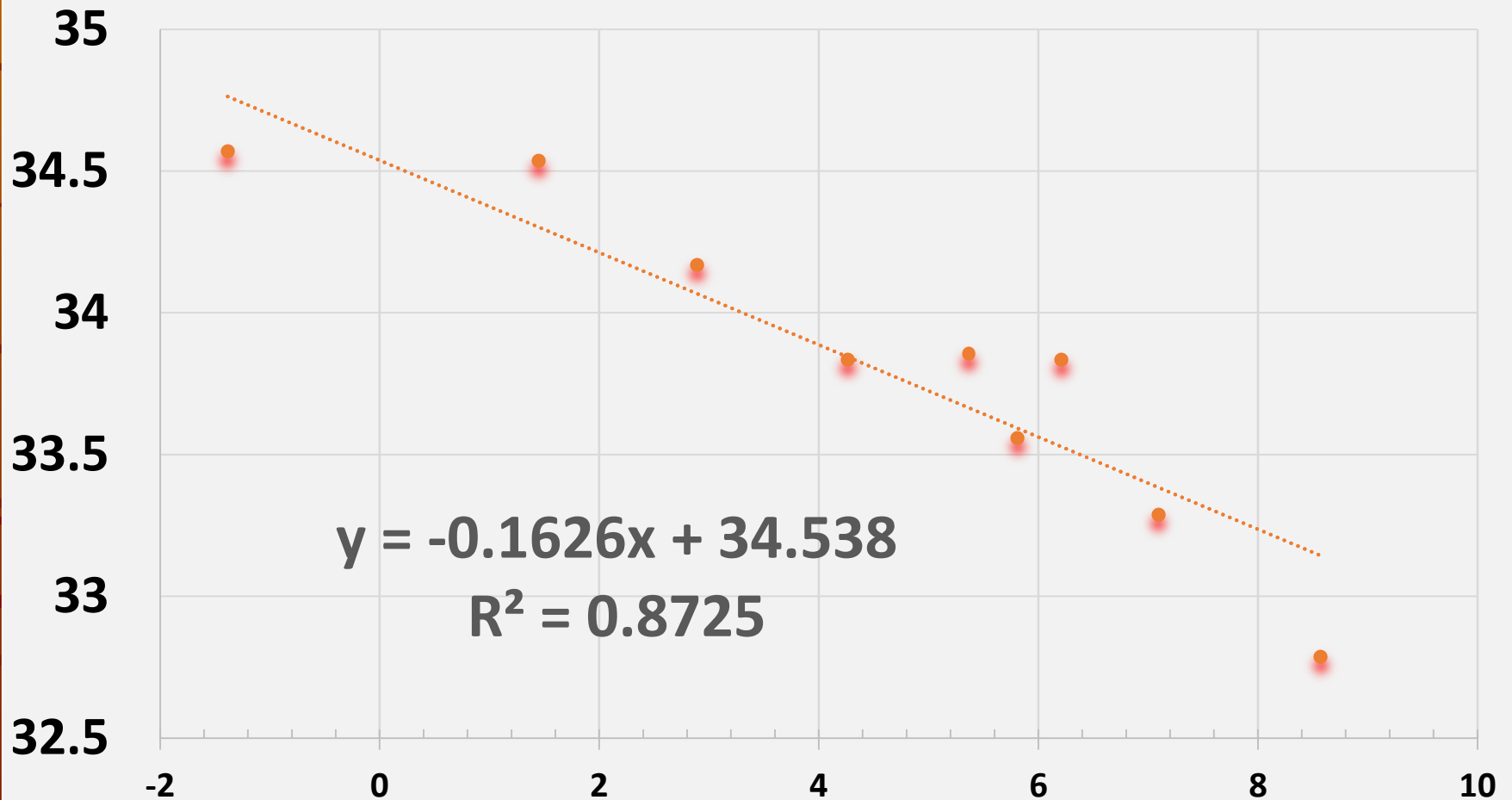
Ellipsometric measurements

Alumina thickness log[time(hr)]-in nm
Si₃N₄ thickness was also fit by program.



Ellipsometric measurements

Al thickness In[time(hr.)] in nm
SiN thickness allowed to vary



Ellipsometric measurements- summary observations,


- ◆ Ellipsometry can be used for time-dependent studies When there's a transparent barrier overlayer
 - The aluminum gets thinner &
 - the aluminum oxide grows thicker
 - ◆ Initial layer is on top of Al
 - Logarithmic behavior suggested
 - Angstrom level resolution is possible.
- ◆ Microchemical analysis could be helpful EDX or XPS.



Take home

- ✦ Spectroscopic Ellipsometry can work as a tool for oxidation of ultrathin layers.
 - work needed to check if these are absolute amounts of materials
- ✦ VUV reflectance studies of insitu mirror is coming along
- ✦ Atomic Hydrogen etches PMMA adequately
 - Also still to be done is:
 - will the polymer block oxidation long enough to put additional barrier layers that are removable

& Acknowledgements



Ben Smith & Paul Allred- helpful conversations
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#PHY1461219

Western Alliance to expand Student opportunities.

An NSF Louis Stokes Alliances for Minority Participation

NASA-space grant consortium – cost share Human
Infrastructure grant 2015- Margaret Miles support.

50 questions about next-generation broadband mirrors for space-based observatories

- ◆ 1 Broadband mirror coatings & aluminum:
- ◆ 2 Understand oxidization of aluminum mirrors
 - characterization tools
- ◆ 3 Barrier layers against oxidation
 - 3.1 Those that stay on-
 - 3.2 Those that come off:
 - ◆ Role of Vacuum deposited/ Vacuum removable barriers-
 - 3.3 point-of-use processing
- ◆ 4 Applications
 - 4.1 **Beyond 15 eV**: Aluminum becomes (partially) transparent below its plasma edge at about 85 nm
 - 4.2 Space observatory applications
- ◆ 5 Practicalities: **How raise TRL.**

Optimizing Reflectance with Aluminum

- ◆ Extends range of UV to ~ 83 nm (15 eV)
- ◆ Transparent at small

